

P-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)
- 100	0.120 at V _{GS} = - 10 V	- 19	16.5 nC
	0.160 at V _{GS} = - 4.5V	- 15.7	

FEATURES

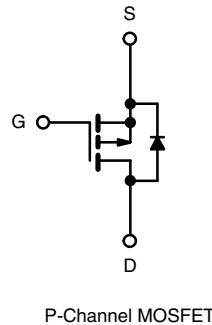
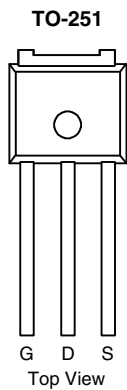
- Halogen-free Option Available
- TrenchFET® Power MOSFET
- UIS and R_g Tested



RoHS
COMPLIANT

APPLICATIONS

- Active Clamp in Intermediate DC/DC Power Supplies



ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 100	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	- 19.0	A
	T _C = 70 °C	- 12.6	
	T _A = 25 °C	- 15 ^{a, b}	
	T _A = 70 °C	- 10 ^{a, b}	
Pulsed Drain Current	I _{DM}	- 20	
Continuous Source-Drain Diode Current	T _C = 25 °C	- 13.2	
	T _A = 25 °C	- 3.0 ^{a, b}	
Avalanche Current	I _{AS}	15	
Single-Pulse Avalanche Energy	E _{AS}	11.25	mJ
Maximum Power Dissipation	T _C = 25 °C	52	W
	T _C = 70 °C	33	
	T _A = 25 °C	3.7 ^{a, b}	
	T _A = 70 °C	2.4	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 50 to 150	°C
Soldering Recommendations (Peak Temperature)		260	

Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
b. t = 10 s.

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, b}	$t \leq 10$ s	R_{thJA}	26	33	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.9	2.4	

Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
b. Maximum under Steady State conditins is 81 °C/W.

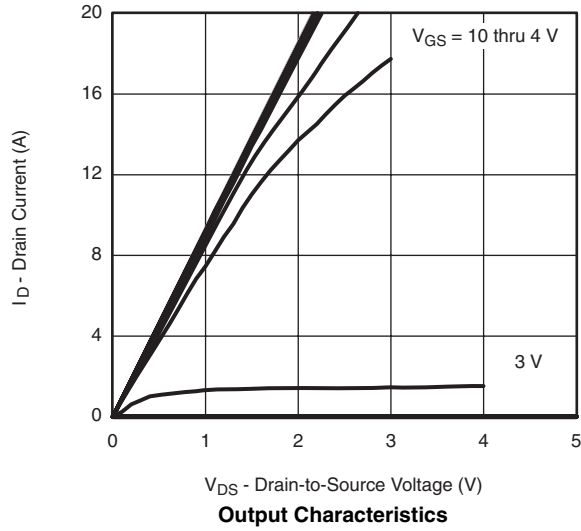
SPECIFICATIONS $T_J = 25$ °C, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0$ V, $I_D = -250$ μ A	- 100			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250$ μ A		- 100		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		- 5.0			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250$ μ A	- 1		- 3	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0$ V, $V_{GS} = \pm 20$ V			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -100$ V, $V_{GS} = 0$ V			- 1	μ A
		$V_{DS} = -100$ V, $V_{GS} = 0$ V, $T_J = 55$ °C			- 10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \geq -5$ V, $V_{GS} = -10$ V	- 10			A
Drain-Source On-State Resistance ^a	$R_{DS(on)}$	$V_{GS} = -10$ V, $I_D = -4$ A		0.108	0.120	Ω
		$V_{GS} = -4.5$ V, $I_D = -3$ A		0.119	0.160	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -15$ V, $I_D = 4$ A		25		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -50$ V, $V_{GS} = 0$ V, $f = 1$ MHz		1480		pF
Output Capacitance	C_{oss}		80			
Reverse Transfer Capacitance	C_{rss}		60			
Total Gate Charge	Q_g	$V_{DS} = -50$ V, $V_{GS} = -10$ V, $I_D = -4$ A		35	55	nC
			$V_{DS} = -50$ V, $V_{GS} = -4.5$ V, $I_D = -4$ A		16.5	
Q_{gs}		4.7				
Q_{gd}		8				
Gate Resistance	R_g	$f = 1$ MHz		5.3	8	Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -50$ V, $R_L = 12.5$ Ω $I_D \cong -4$ A, $V_{GEN} = -4.5$ V, $R_g = 1$ Ω		30	45	ns
Rise Time	t_r			110	165	
Turn-Off DelayTime	$t_{d(off)}$			51	80	
Fall Time	t_f			40	60	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -50$ V, $R_L = 12.5$ Ω $I_D \cong -4$ A, $V_{GEN} = -10$ V, $R_g = 1$ Ω		11	18	
Rise Time	t_r			13	20	
Turn-Off DelayTime	$t_{d(off)}$			42	65	
Fall Time	t_f			10	15	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25$ °C			- 19	A
Pulse Diode Forward Current ^a	I_{SM}				- 20	
Body Diode Voltage	V_{SD}	$I_S = -3$ A		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -4$ A, $di/dt = 100$ A/ μ s, $T_J = 25$ °C		46	70	ns
Body Diode Reverse Recovery Charge	Q_{rr}			97	150	nC
Reverse Recovery Fall Time	t_a			36		ns
Reverse Recovery Rise Time	t_b			10		

Notes:

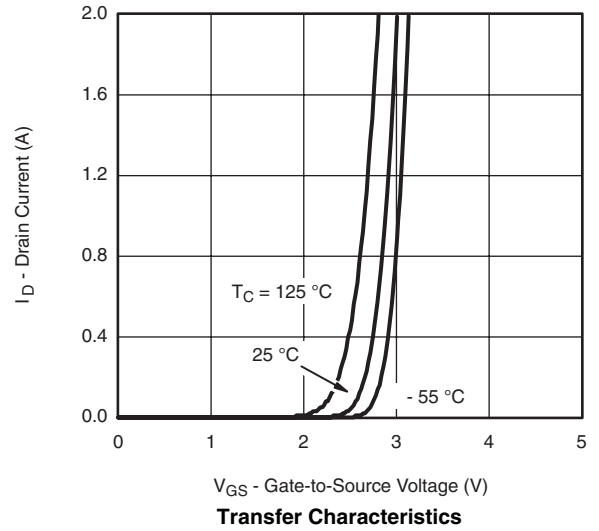
- a. Pulse test; pulse width ≤ 300 μ s, duty cycle ≤ 2 %.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

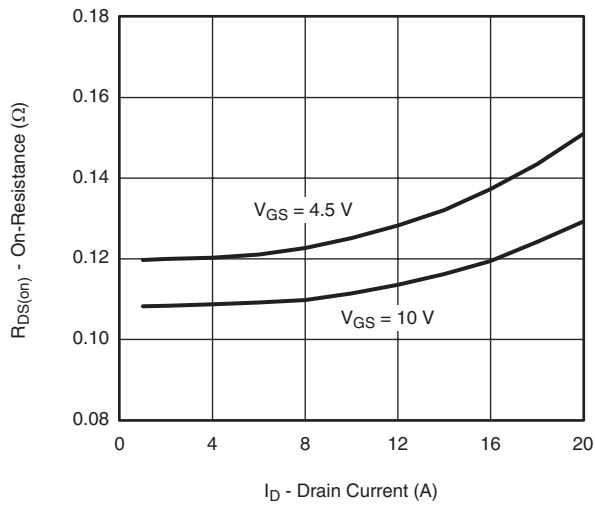
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



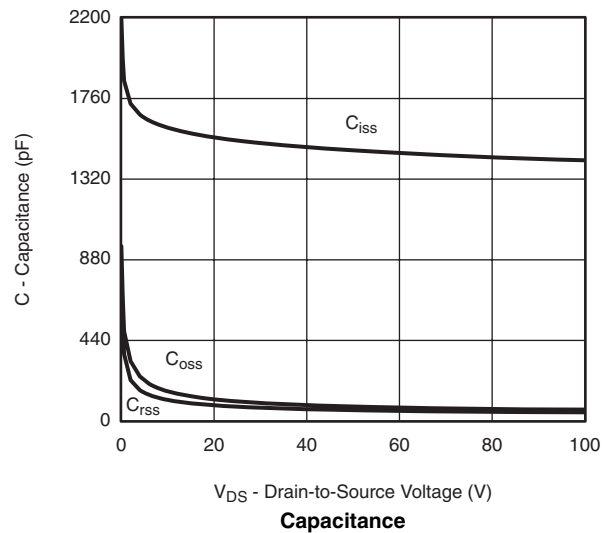
V_{DS} - Drain-to-Source Voltage (V)
Output Characteristics



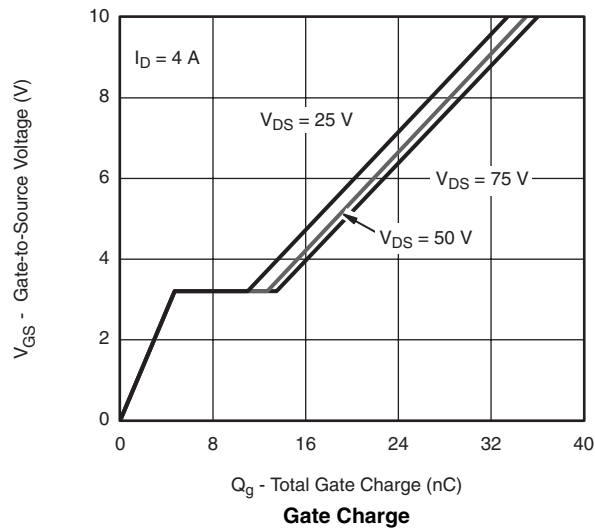
V_{GS} - Gate-to-Source Voltage (V)
Transfer Characteristics



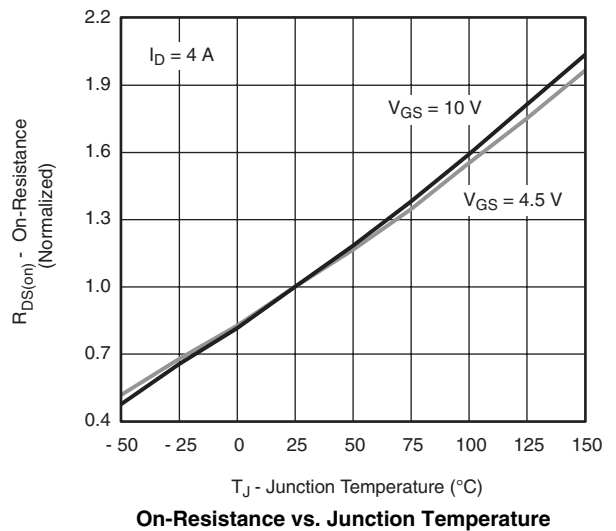
On-Resistance vs. Drain Current and Gate Voltage



Capacitance

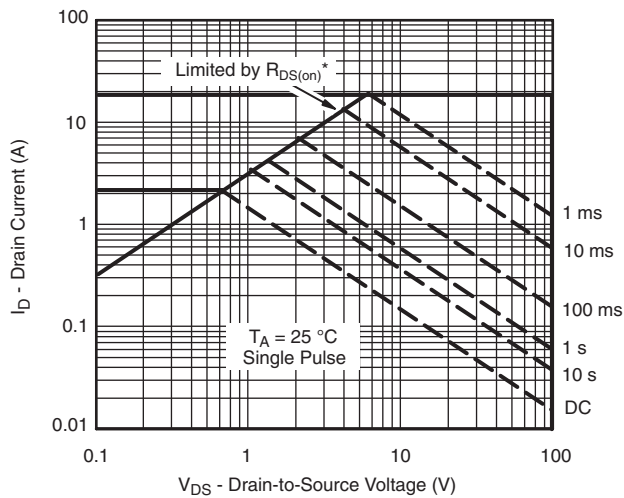
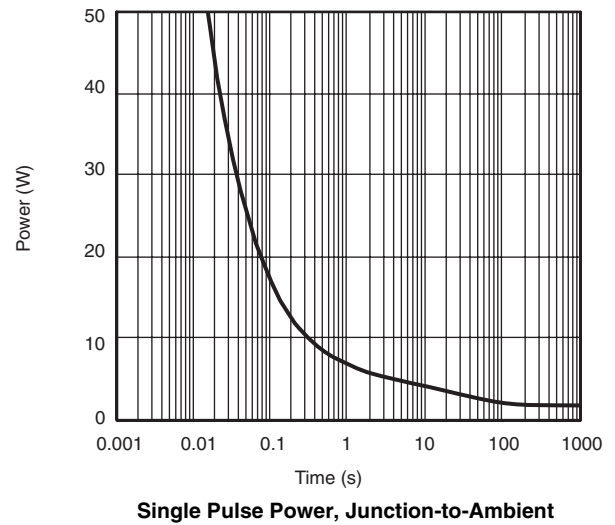
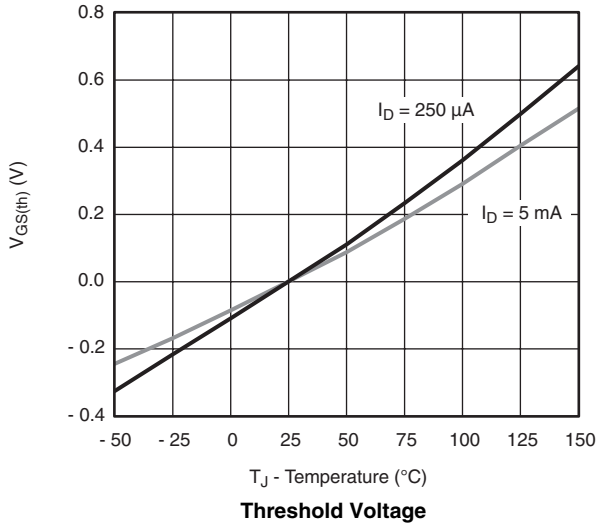
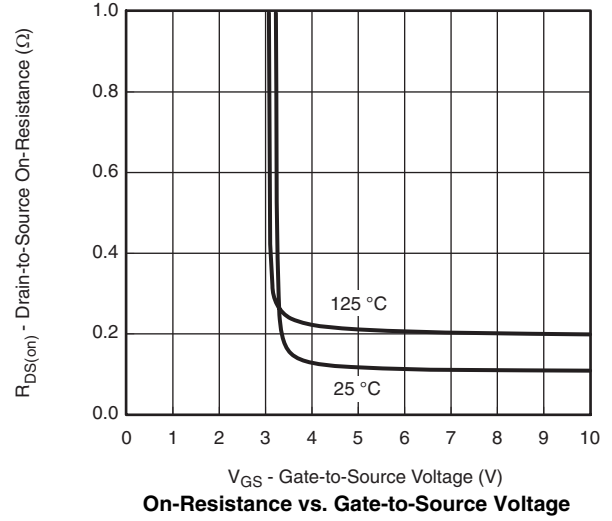
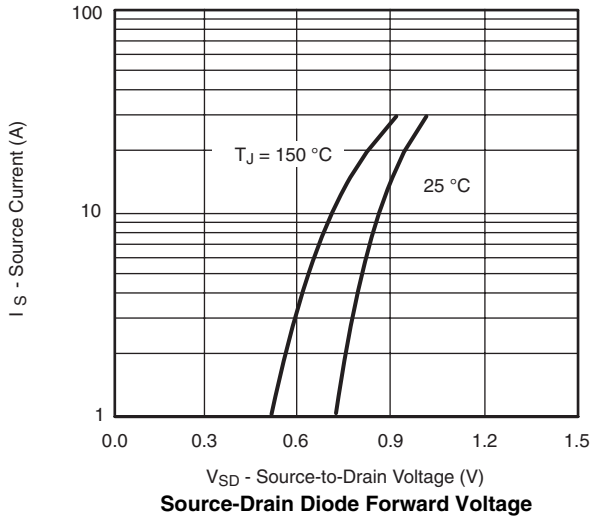


Gate Charge



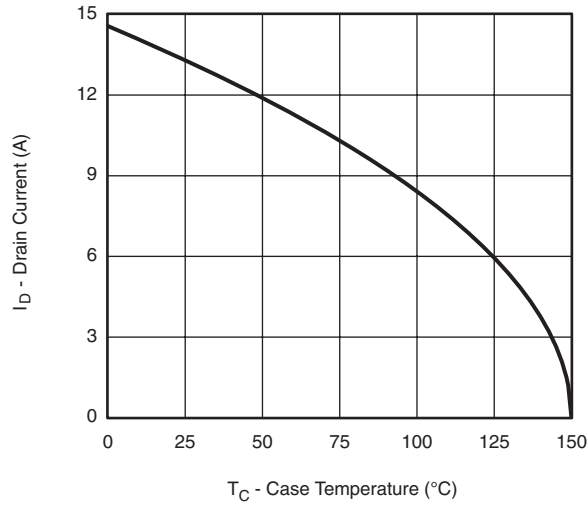
On-Resistance vs. Junction Temperature

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

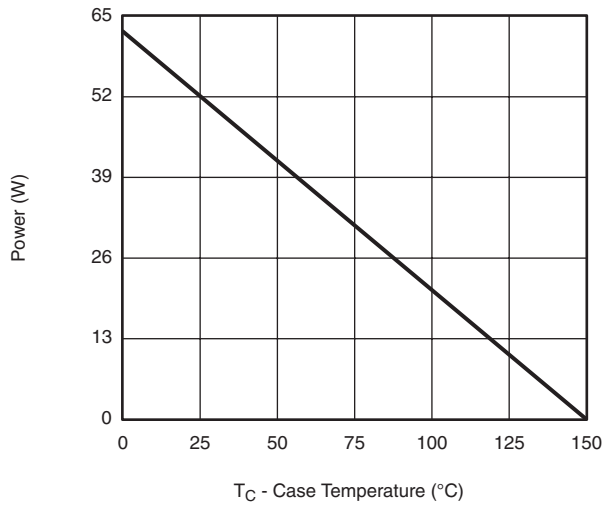


* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

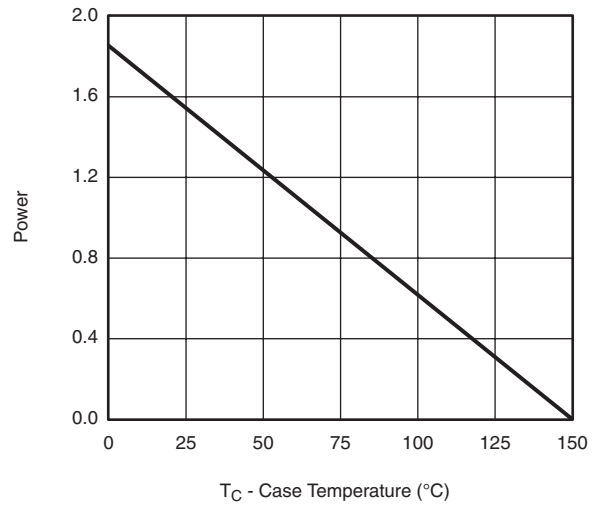
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Current Derating*



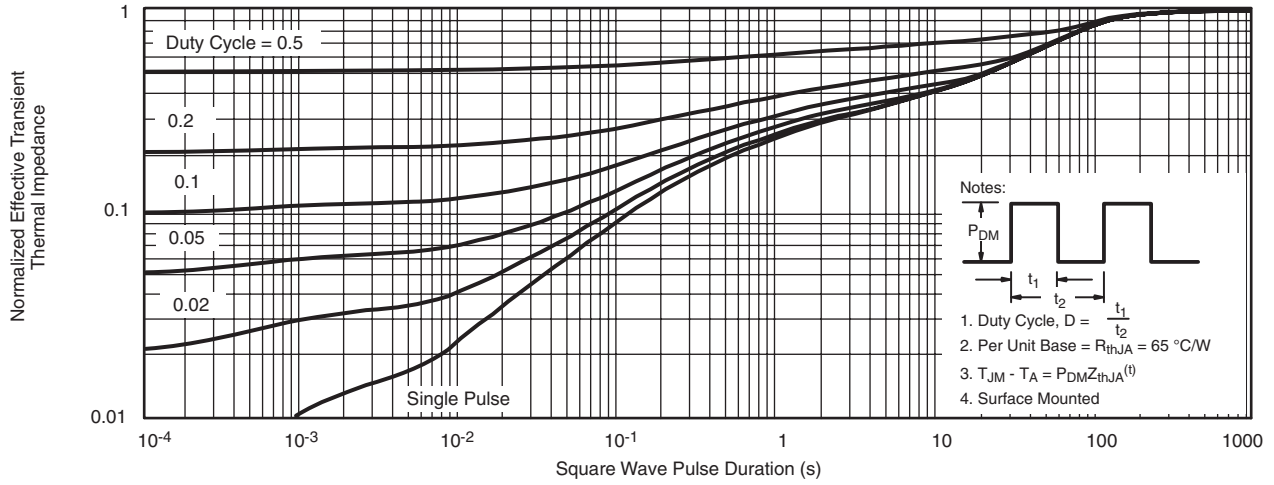
Power, Junction-to-Case



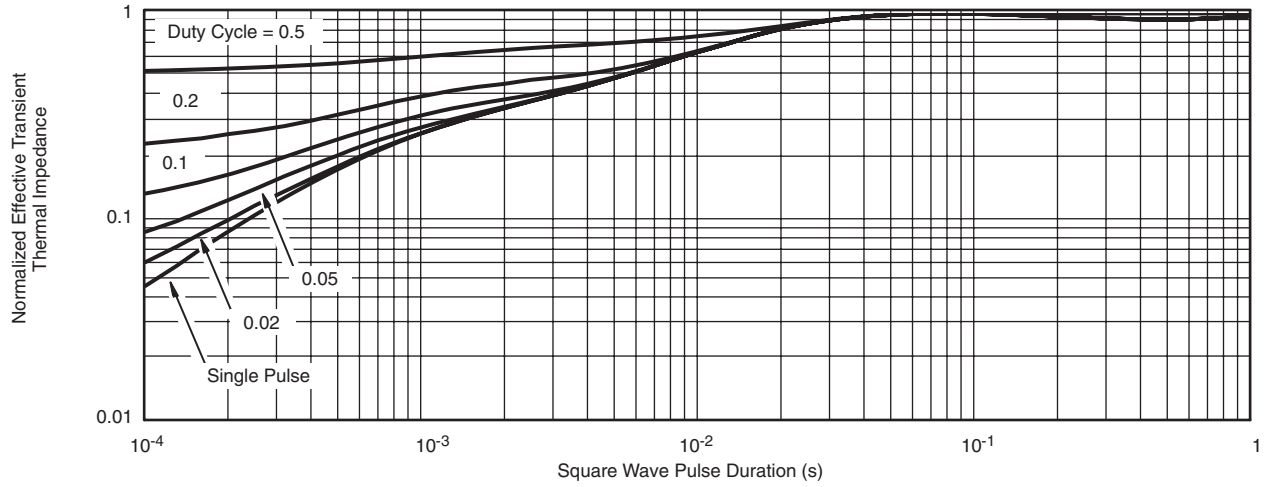
Power, Junction-to-Ambient

* The power dissipation PD is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

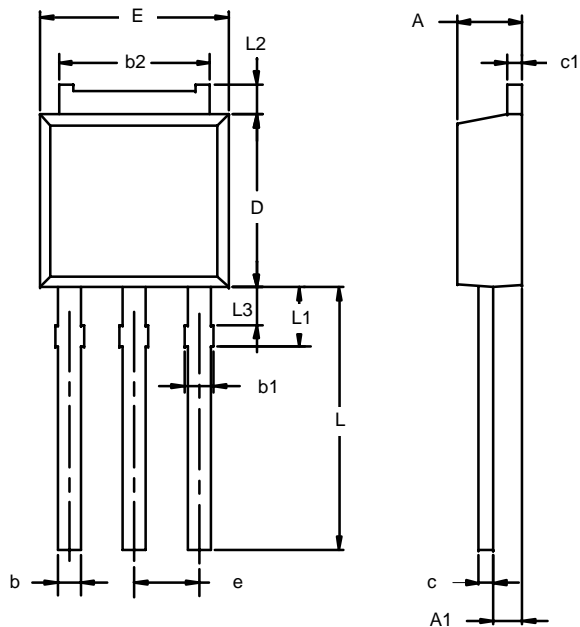


Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

Dim	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
c	0.46	0.58	0.018	0.023
c1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
E	6.48	6.73	0.255	0.265
e	2.28 BSC		0.090 BSC	
L	8.89	9.53	0.350	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346				

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